## Laser Fabrication of Hybrid Electrodes Composed of Nanocarbons Mixed with Cerium and Manganese Oxides for Supercapacitive Energy Storage

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## SUPPORTING MATERIAL

Dispersion	Thickness (µm)
GO-Ce	$1.4 \pm 0.2$
CNT-Ce	$1.2 \pm 0.1$
GO-CNT-Ce-515	$1.7 \pm 0.2$
GO-CNT-Ce-525	$1.1 \pm 0.1$
GO-CNT-Ce-Mn-5151	$1.3 \pm 0.2$
GO-CNT-Ce-Mn-5152	$1.3 \pm 0.2$
GO-CNT-Ce-Mn-5155	$1.4 \pm 0.3$

Table S1. Average thickness of the fabricated electrodes.



Figure S1. XHRSEM images at 5000x of a) GO-Ce, b) CNT-Ce, c) GO-CNT-Ce-515, and d) GO-CNT-Ce-Mn-5151.



Figure S2. XHRSEM images at 100000x of a) GO-Ce, b) CNT-Ce, c) GO-CNT-Ce-515, and d) GO-CNT-Ce-Mn-5151.



Figure S3. XHRSEM images at 500000x of a) GO-CNT-Ce-Mn-5151, b) GO-CNT-Ce-Mn-5152, and c) GO-CNT-Ce-Mn-5155.



*Figure S4. XHRSEM images at 100000x of a) GO-CNT-Ce-515, and b) GO-CNT-Ce-525. Regions with agglomerated CNTs are indicated.* 



Figure S5. HRTEM of GO-CNT-Ce-515 with highlighted different crystalline regions.



Figure S6. Integrated area of XPS a) C1s and b) O1s high resolution spectra.



Figure S7. Ce  $3d_{3/2}$  and Ce  $3d_{5/2}$  high resolutions XPS of CeO<sub>2</sub>-raw nanoparticles and GO-CNT-Ce-515 for comparison.



Figure S8. a) Volumetric capacitance vs sweep rate of GO-CNT-Ce-Mn-5152 for diverse thicknesses and b) volumetric capacitance vs thickness for different sweep rates.



Figure S9 Equivalent circuit for data fitting

				CPE1		CPE2	
	R1 (Ω)	R2 (Ω)	R3 (Ω)	Υ (μS s <sup>n</sup> )	n	Υ (μS s <sup>n</sup> )	n
GO-Ce	13.4	51.4	886.1	25.8	0.82	36.0	0.84
CNT-Ce	15.4	225.3	10991	14.2	0.85	52.8	0.89

Table S2. Fitting values for the elements of the equivalent circuit.

GO-CNT-Ce-515	13.8	30.7	1881.3	38.1	0.83	25.5	0.94
GO-CNT-Ce-525	14.4	25.7	2564.1	23.3	0.84	22.9	0.91
GO-CNT-Ce-Mn-5151	17.5	64.8	1659.9	16.3	0.86	63.6	0.87
GO-CNT-Ce-Mn-5152	15.1	63.3	1855.3	14.4	0.87	77.8	0.84
GO-CNT-Ce-Mn-5155	15.2	525.8	6447.4	10.6	0.88	83.0	0.88